

N-Channel Enhancement Mode Power MOSFET

Description

The HM40N10 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

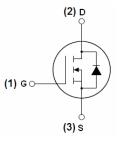
- V_{DS} = 100V, I_{D} =40A $R_{DS(ON)}$ < 17mΩ @ V_{GS} =10V (Typ:14mΩ)
- Special process technology for high ESD capability
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



100% AVds TESTED!



Schematic diagram



Marking and pin assignment



TO-220-3L top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM40N10	HM40N10	TO-220-3L	-	-	-

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	100	V
Gate-Source Voltage	V _G s	±20	V
Drain Current-Continuous	I _D	40	А
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	28	Α
Pulsed Drain Current	I _{DM}	160	Α
Maximum Power Dissipation	P _D	140	W
Derating factor	-	0.94	W /℃
Single pulse avalanche energy (Note 5)	E _{AS}	520	mJ
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 175	$^{\circ}$ C



Thermal Characteristic

Thermal Resistance, Junction-to-Case(Note 2)	$R_{ heta JC}$	1.07	°C/W	
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Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	100	110	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	·					
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2	3	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =28A	-	14	17	mΩ
Forward Transconductance	g FS	V _{DS} =25V,I _D =28A	32	-	-	S
Dynamic Characteristics (Note4)			•			
Input Capacitance	C _{lss}	\/ 00\/\/ 0\/	-	3400	-	PF
Output Capacitance	C _{oss}	V_{DS} =30V, V_{GS} =0V, F=1.0MHz	-	290	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.UIVIDZ	-	221	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	15	-	nS
Turn-on Rise Time	t _r	VDD=30V,ID=2A,RL=15Ω,	-	11	-	nS
Turn-Off Delay Time	t _{d(off)}	RG=2.5Ω,VGS=10V	-	52	-	nS
Turn-Off Fall Time	t _f		-	13	-	nS
Total Gate Charge	Qg		-	94	-	nC
Gate-Source Charge	Q _{gs}	ID=30A,VDD=30V,VGS=10V	-	16	-	nC
Gate-Drain Charge	Q_{gd}		-	24	-	nC
Drain-Source Diode Characteristics			•			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =28A	-	0.85	1.2	V
Diode Forward Current (Note 2)	Is		-	-	40	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 28A	-	33		nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs(Note3)	-	54		nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+				y LS+LD)

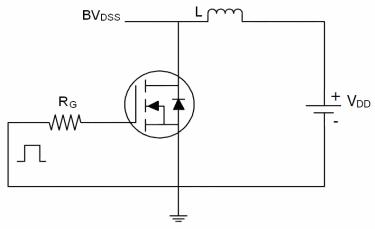
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- **4.** Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25 $^{\circ}$ C,V_{DD}=50V,V_G=10V,L=0.5mH,Rg=25 Ω

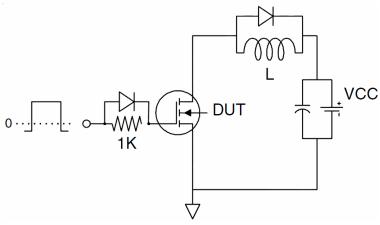


Test Circuit

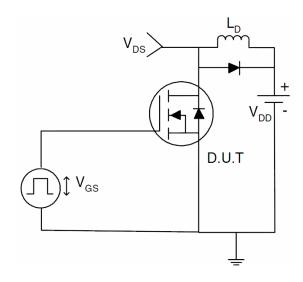
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit





Typical Electrical and Thermal Characteristics (Curves)

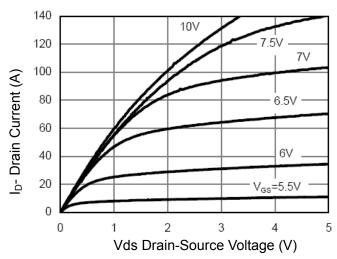


Figure 1 Output Characteristics

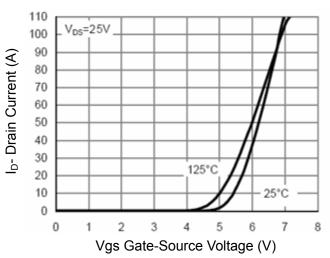


Figure 2 Transfer Characteristics

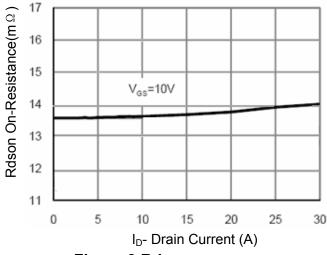


Figure 3 Rdson- Drain Current

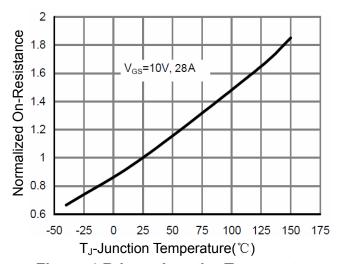


Figure 4 Rdson-JunctionTemperature

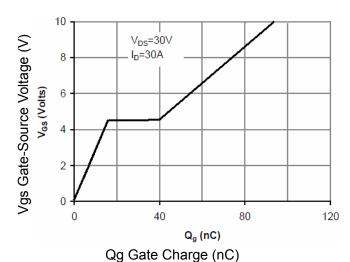


Figure 5 Gate Charge

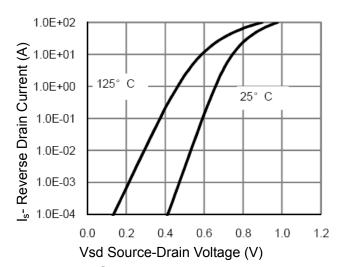


Figure 6 Source- Drain Diode Forward



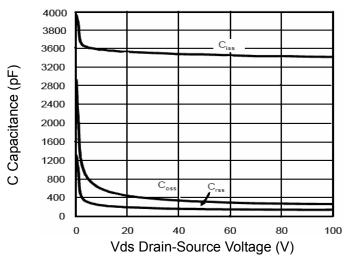


Figure 7 Capacitance vs Vds

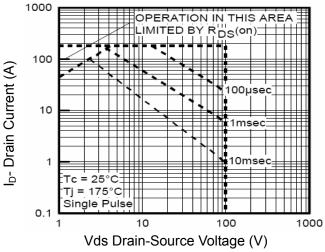


Figure 8 Safe Operation Area

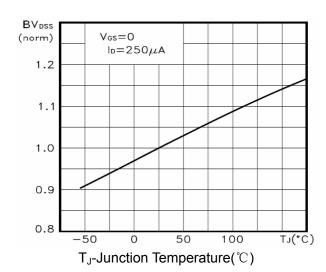


Figure 9 BV_{DSS} vs Junction Temperature

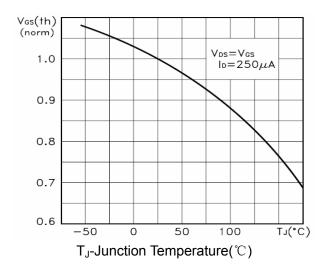


Figure 10 V_{GS(th)} vs Junction Temperature

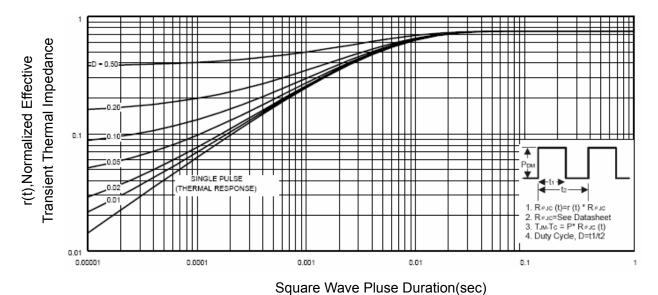
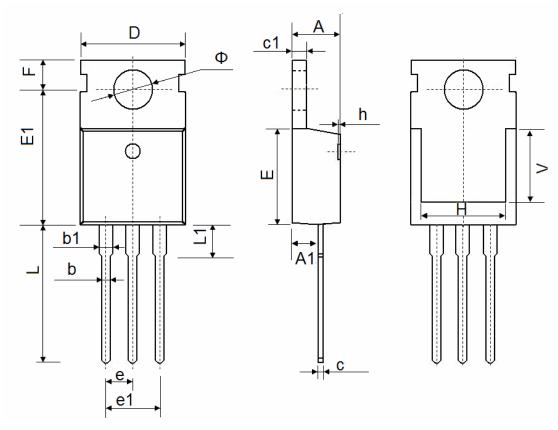


Figure 11 Normalized Maximum Transient Thermal Impedance



TO-220-3L Package Information



Comple of	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
А	4.400	4.600	0.173	0.181	
A1	2.250	2.550	0.089	0.100	
b	0.710	0.910	0.028	0.036	
b1	1.170	1.370	0.046	0.054	
С	0.330	0.650	0.013	0.026	
c1	1.200	1.400	0.047	0.055	
D	9.910	10.250	0.390	0.404	
E	8.9500	9.750	0.352	0.384	
E1	12.650	12.950	0.498	0.510	
е	2.540	TYP.	0.100	TYP.	
e1	4.980	5.180	0.196	0.204	
F	2.650	2.950	0.104	0.116	
Н	7.900	8.100	0.311	0.319	
h	0.000	0.300	0.000	0.012	
L	12.900	13.400	0.508	0.528	
L1	2.850	3.250	0.112	0.128	
V	7.500	REF.	0.295	REF.	
Ф	3.400	3.800	0.134	0.150	



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